



128Kx8 Plastic Monolithic SRAM

FEATURES

- Fast Access Times of 15*, 17*, 20, 25ns
- 2V Data Retention (EDI88130LPS)
 - Battery Back-up Operation
- $\overline{CS}_1$, CS_2 & $\overline{OE}$ Functions for Bus Control
- Inputs and Outputs Directly TTL Compatible
- Fully Static, No Clocks
- Industrial and Military Temperature Ranges
- Surface Mount Package
 - 32 pin Plastic SOJ (Package 7)
- Single +5V ($\pm 10\%$) Supply Operation

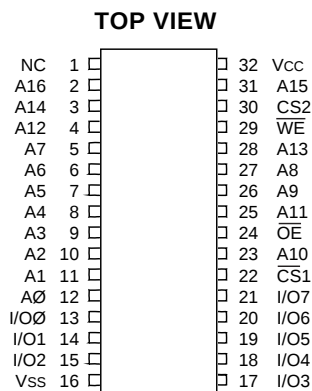
* Industrial Temperature Range Only

The EDI88130CS-RP is a ruggedized plastic 128Kx8 monolithic Static RAM that allows the user to capitalize on the cost advantage of using a plastic component while not sacrificing all of the reliability available in a full military device.

Extended temperature testing is performed with the test patterns developed for use on WEDC's fully compliant 128Kx8 SRAMs. WEDC fully characterizes devices to determine the proper test patterns for testing at temperature extremes. This is critical because the operating characteristics of device change when it is operated beyond the commercial temperature range. Using commercial test methods will not guarantee a device that operates reliably in the field at temperature extremes. Users of WEDC's ruggedized plastic benefit from WEDC's extensive experience in characterizing SRAMs for use in military systems.

WEDC ensures Low Power devices will retain data in Data Retention mode by characterizing the devices to determine the appropriate test conditions. This is crucial for systems operating at -40°C or below and using dense memories such as 128Kx8s. WEDC's ruggedized plastic SOJ is footprint compatible with WEDC's full military ceramic 32 pin SOJ.

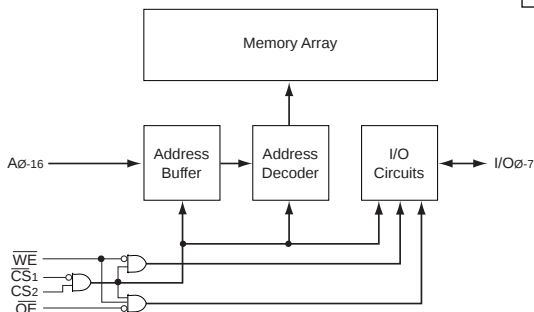
FIG. 1 PIN CONFIGURATION

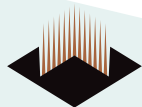


PIN DESCRIPTION

I/O0-7	Data Inputs/Outputs
A0-16	Address Inputs
$\overline{WE}$	Write Enable
$\overline{CS}_1$, CS_2	Chip Selects
$\overline{OE}$	Output Enable
V _{CC}	Power (+5V $\pm 10\%$)
V _{SS}	Ground
NC	Not Connected

BLOCK DIAGRAM





ABSOLUTE MAXIMUM RATINGS

Parameter		Unit
Voltage on any pin relative to Vss	-0.2 to 7.0	V
Operating Temperature TA (Ambient)		
Industrial	-40 to +85	°C
Military	-55 to +125	°C
Storage Temperature, Plastic	-65 to +125	°C
Power Dissipation	1.7	W
Output Current	40	mA
Junction Temperature, TJ	175	°C

NOTE:

Stress greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions greater than those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	Vcc	4.5	5.0	5.5	V
Supply Voltage	Vss	0	0	0	V
Input High Voltage	VIH	2.2	—	Vcc +0.3	V
Input Low Voltage	VIL	-0.3	—	+0.8	V

TRUTH TABLE

OE	CS1	CS2	WE	Mode	Output	Power
X	H	X	X	Standby	High Z	Icc2, Icc3
X	X	L	X	Standby	High Z	Icc2, Icc3
H	L	H	H	Output Deselect	High Z	Icc1
L	L	H	H	Read	Data Out	Icc1
X	L	H	L	Write	High Z	Icc1

CAPACITANCE

(TA = +25°C)

Parameter	Symbol	Condition	Max SOJ	Unit
Address Lines	CI	VIN = Vcc or Vss, f = 1.0MHz	8	pF
Data Lines	CO	VOU = Vcc or Vss, f = 1.0MHz	10	pF

These parameters are sampled, not 100% tested.

DC CHARACTERISTICS

(Typical: Vcc = 5V, TA = 25°C)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Input Leakage Current	ILI	VIN = 0V to Vcc	—	—	±5	µA
Output Leakage Current	ILO	VI/O = 0V to Vcc, CS1 ≥ VIH and/or CS2 ≤ VIL	—	—	±5	µA
Operating Power Supply Current	Icc1	WE, CS1 = VIL, IIO = 0mA, CS2 = VIH (15-17ns)	—	—	300	mA
		(20-25ns)	—	—	225	mA
Standby (TTL) Power Supply Current	Icc2	CS1 ≥ VIH and/or CS2 ≤ VIL, VIN ≥ VIH or ≤ VIL	—	—	35	mA
Full Standby Power Supply Current	Icc3	CS1 ≥ Vcc -0.2V and/or CS2 ≤ 0.2V VIN ≥ Vcc -0.2V or VIN ≤ 0.2V	—	—	20	mA
		CS LPS	—	—	10	mA
Output Low Voltage	VOL	IOL = 8.0mA	—	—	0.4	V
Output High Voltage	VOH	IOH = -4.0mA	2.4	—	—	V

AC TEST CONDITIONS

Figure 1

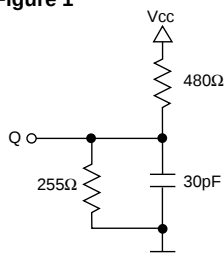
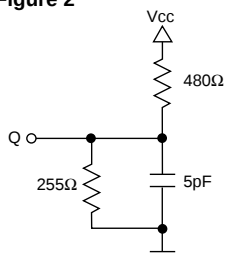


Figure 2



Input Pulse Levels	Vss to 3.0V
Input Rise and Fall Times	3ns
Input and Output Timing Levels	1.5V
Output Load	Figure 1

NOTE: For tEHQZ, tGHQZ and twLQZ, CL = 5pF Figure 2)



AC CHARACTERISTICS – READ CYCLE

(V_{CC} = 5.0V, V_{SS} = 0V, T_A = -55°C to +125°C)

Parameter	Symbol		15ns*		17ns*		20ns		25ns		Units
	JEDEC	Alt.	Min	Max	Min	Max	Min	Max	Min	Max	
Read Cycle Time	tAVAV	tRC	15		17		20		25		ns
Address Access Time	tAVQV	tAA		15		17		20		25	ns
Chip Select Access Time	tE1LQV	tACS		15		17		20		25	ns
	tE2HQV	tACS		15		17		20		25	ns
Chip Select to Output in Low Z (1)	tE1LQX	tCLZ	5		5		5		5		ns
	tE2HQX	tCLZ	5		5		5		5		ns
Chip Disable to Output in Low Z (1)	tE1HQZ	tCHZ		6		7		8		10	ns
	tE2LQZ	tCHZ		6		7		8		10	ns
Output Hold from Address Change	tAVQX	tOH	3		3		3		3		ns
Output Enable to Output Valid	tGLQV	tOE		6		6		7		8	ns
Output Enable to Output in Low Z (1)	tGLQX	tOLZ	0		0		0		0		ns
Output Disable to Output in High Z(1)	tGHQZ	tOHZ		5		6		7		9	ns
Chip Enable to Power Up (1)	tE1LICCH	tPU	0		0		0		0		ns
	tE2HICCH	tPU	0		0		0		0		ns
Chip Enable to Power Down (1)	tE1HICCL	tPD		15		17		20		25	ns
	tE2LICCL	tPD		15		17		20		25	ns

* Industrial Temperature Range Only

1. This parameter is guaranteed by design but not tested.

AC CHARACTERISTICS – WRITE CYCLE

(V_{CC} = 5.0V, V_{SS} = 0V, T_A = -55°C to +125°C)

Parameter	Symbol		15ns*		17ns*		20ns		25ns		Units
	JEDEC	Alt.	Min	Max	Min	Max	Min	Max	Min	Max	
Write Cycle Time	tAVAV	tWC	15		17		20		25		ns
Chip Select to End of Write	tE1LWH	tCW	12		13		15		16		ns
	tE1LE1H	tCW	12		13		15		16		ns
	tE2HWH	tCW	12		13		15		16		ns
	tE2HE2L	tCW	12		13		15		16		ns
Address Setup Time	tAVWL	tAS	0		0		0		0		ns
	tAVE1L	tAS	0		0		0		0		ns
	tAVE2H	tAS	0		0		0		0		ns
Address Valid to End of Write	tAVWH	tAW	12		13		15		16		ns
Write Pulse Width	tWLWH	tWP	12		13		15		16		ns
	tWLE1H	tWP	12		13		15		16		ns
	tWLE2L	tWP	12		13		15		16		ns
Write Recovery Time	tWHAX	tWR	0		0		0		0		ns
	tE1HAX	tWR	0		0		0		0		ns
	tE2LAX	tWR	0		0		0		0		ns
Data Hold Time	tWHDX	tDH	0		0		0		0		ns
	tE1HDX	tDH	0		0		0		0		ns
	tE2LDX	tDH	0		0		0		0		ns
Write to Output in High Z (1)	tWLQZ	tWHZ	0	7	0	8	0	8	0	10	ns
Data to Write Time	tDVWH	tDW	7		8		8		10		ns
	tDVE1H	tDW	7		8		8		10		ns
	tDVE2L	tDW	7		8		8		10		ns
Output Active from End of Write (1)	tWHQX	tWLZ	3		3		3		3		ns

* Industrial Temperature Range Only

1. This parameter is guaranteed by design but not tested.



FIG. 2 TIMING WAVEFORM - READ CYCLES

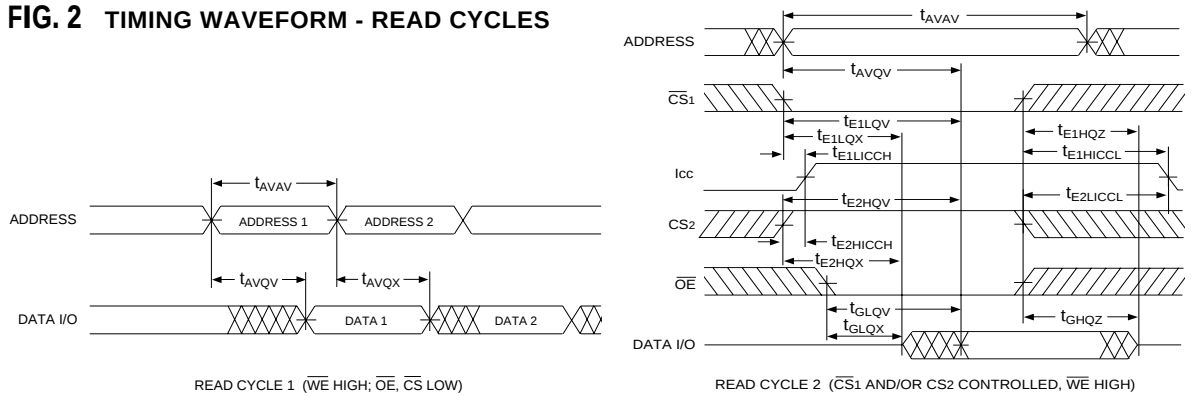


FIG. 3 WRITE CYCLE 1

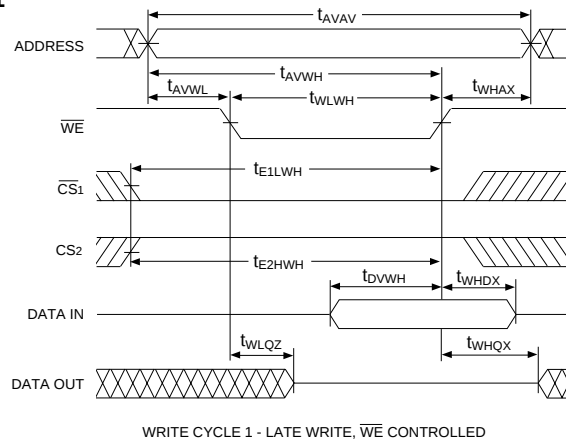
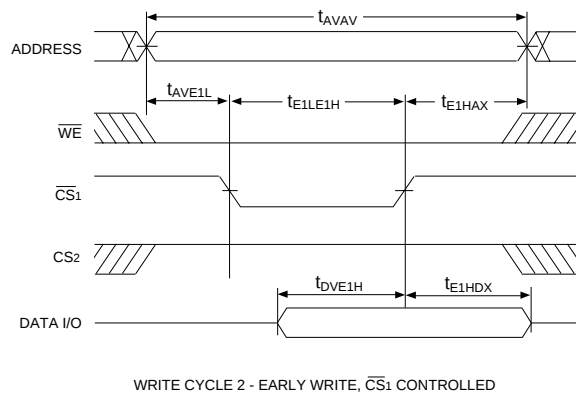
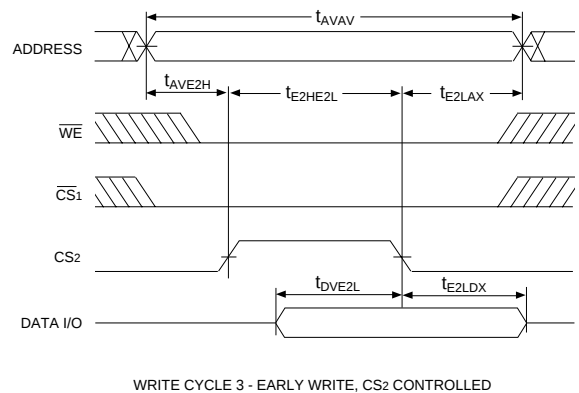


FIG. 4 WRITE CYCLES 2



WRITE CYCLES 3





DATA RETENTION CHARACTERISTICS (EDI88130LPS ONLY)

(TA = -55°C to +125°C)

Characteristic Low Power Version only	Sym	Conditions	Min	Typ	Max	Units
Data Retention Voltage	V _{DD}	V _{DD} = 2.0V	2	–	–	V
Data Retention Quiescent Current	I _{CCDR}	$\overline{CS1} \geq V_{DD} - 0.2V$ and/or $CS2 \geq V_{SS} + 0.2V$	–	0.5	3	mA
Chip Disable to Data Retention Time (1)	T _{CDR}	V _{IN} ≥ V _{DD} - 0.2V	0	–	–	ns
Operation Recovery Time (1)	T _R	or V _{IN} ≤ 0.2V	T _{AVAV} *	–	–	ns

NOTE:

1. Parameter guaranteed by design, but not tested.

* Read Cycle Time

FIG. 5
DATA RETENTION - $\overline{CS1}$ CONTROLLED

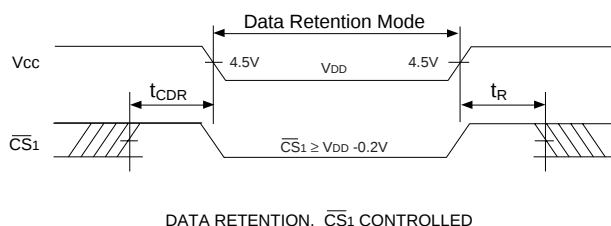
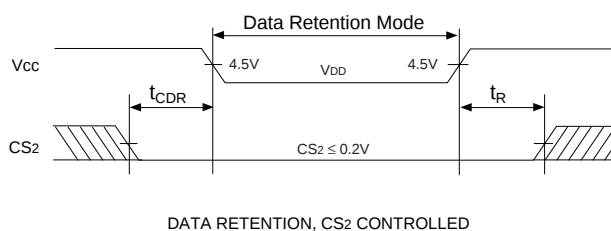
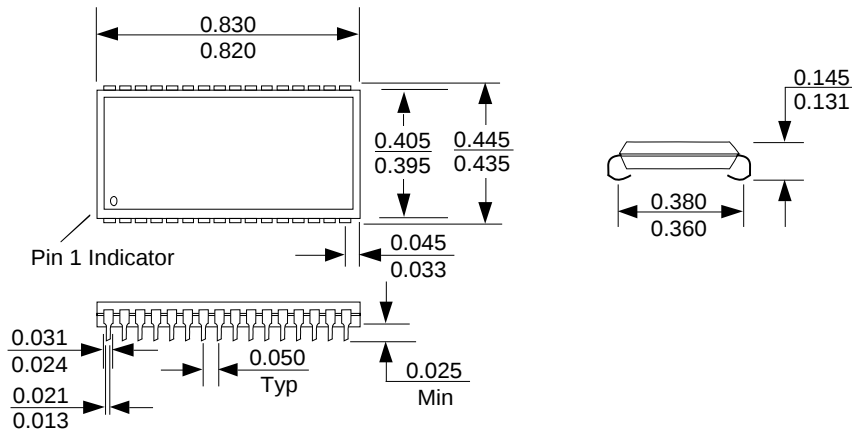


FIG. 6
DATA RETENTION - CS2 CONTROLLED





PACKAGE 7: 32 PIN PLASTIC SOJ



ALL DIMENSIONS ARE IN INCHES

ORDERING INFORMATION

EDI 8 8 130 CS X X X

WHITE ELECTRONIC DESIGNS _____

SRAM _____

ORGANIZATION, 128Kx8 _____
(130 = Dual Chip Select)

TECHNOLOGY: _____
CS = CMOS Standard Power (5V)
LPS = Low Power

ACCESS TIME (ns) _____

PACKAGE TYPE: _____
M = 32 pin Plasticic SOJ (Package 7)

DEVICE GRADE: _____
M = Military Screened -55°C to +125°C
I = Industrial -40°C to +85°C